

U.S. Patent Application Serial No. 10/565,156  
Response to OA dated May 12, 2008

### REMARKS

Applicants have amended the claims in order to remove the objections thereto and to clarify the present invention. The Applicants respectfully submit that no new matter has been added. It is believed that this Amendment is fully responsive to the Office Action dated April 2, 2009.

As amended, the claims specify that the contact part is curved when a temperature of the contact part changes. In other words, an "event", a temperature change of the contact part, occurs to cause the contact part to be curved.

In the Office Action, Claim 1 was rejected under 35 U.S.C. §102(b) as being anticipated by Yoshida et al. (U.S. Patent No. 6,710,608) and Claim 2 was rejected under 35 U.S.C. §103(a) as being unpatentable over Yoshida et al. and further in view of Maruyama et al. (U.S. Patent No. 6,791,345), Flechsig et al. (U.S. Patent No. 7,176,703) or Ding et al. (U.S. Patent No. 6,477,147).

Reconsideration and removal of these rejections are respectfully requested in view of the present claim amendments and the following remarks.

With respect to the rejection of Claim 1 based on Yoshida, Yoshida discloses a contact probe (1F) as shown in FIG. 36, having wiring patterns (3F) of metal in a generally L shape and a resin film (2F) having a larger width than the wiring patterns. The wiring patterns 2 F are attached to the resin film (2F) in spaced relationship.

The probe, as now claimed in amended Claim 1, has distinct features that its contact part has a base part being formed of a first metal having a first thermal expansion coefficient and a junction part which is formed of a second metal having a second thermal expansion coefficient different from

U.S. Patent Application Serial No. 10/565,156  
Response to OA dated May 12, 2008

that of the first metal and provided integrally along the base part exclusive of the tip. The junction part has the same width as that of the base part.

Amendments to Claim 1 clarify distinctive features of the probe that the base part and the junction part are both formed of metal and that the junction part has a width of the base part. The claimed probe is distinctly different from the contact probe (1F) of Yoshida formed by attaching wiring patterns (3F) to the resin film (2F) of a larger width. Therefore, it is respectfully submitted that the present claimed probe is distinct from and unobvious in view of Yoshida and amended Claim 1 is believed to be patentable.

With respect to the rejection of Claim 2, it is respectfully submitted that the probe of Yoshida is distinct from the configuration now claimed. The probe as now claimed in amended Claim 2 is defined such that the base part and the junction part are both formed of metal and the junction part has the same width as that of the base part. It is respectfully submitted that it would not have been obvious for those skilled in the art to arrive at the amended claimed probe by replacing the resin film (2F) with a shape memory alloy as disclosed by the cited art of Maruyama, Plechsig et al. Or Ding et al.

In view of the aforementioned amendments and accompanying remarks, Claims 1-2, as amended, are believed to be patentable and in condition for allowance, which action, at an early date, is requested.

If, for any reason, it is felt that this application is not now in condition for allowance, the Examiner is requested to contact the Applicants' undersigned attorney at the telephone number

RECEIVED  
CENTRAL FAX CENTER

AUG 03 2009

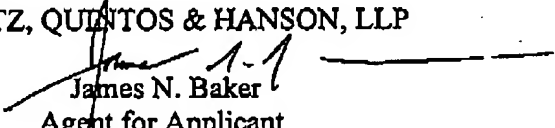
U.S. Patent Application Serial No. 10/565,156  
Response to OA dated May 12, 2008

indicated below to arrange for an interview to expedite the disposition of this case.

In the event that this paper is not timely filed, the Applicants respectfully petition for an appropriate extension of time. Please charge any fees for such an extension of time and any other fees which may be due with respect to this paper, to Deposit Account No. 01-2340.

Respectfully submitted,

KRATZ, QUINTOS & HANSON, LLP

  
James N. Baker  
Agent for Applicant  
Reg. No. 40,899

JNB/ak

Atty. Docket No. 050753  
Suite 400  
1420 K Street, N.W.  
Washington, D.C. 20005  
(202) 659-2930



23850

PATENT & TRADE MARK OFFICE

Enclosure: Petition for Extension of Time